

Report No.: SHEM200100031602

Page: 1 of 9

Cover Page

RF Exposure Evaluation Report

Application No.: SHEM2001000316CR

FCC ID: 2ADTD-I0F2502 IC: 20199-I0F2502

Hangzhou Hikvision Digital Technology Co., Ltd. Applicant:

No. 555 Qianmo Road, Binjiang District, Hangzhou 310052, China **Address of Applicant:**

Manufacturer: Hangzhou Hikvision Digital Technology Co., Ltd.

Address of Manufacturer: No. 555 Qianmo Road, Binjiang District, Hangzhou 310052, China

1. Hangzhou Hikvision Technology Co., Ltd.

2. Hangzhou Hikvision Electronics Co., Ltd. **Factory:**

3. Hangzhou Hikvision Digital Technology Co., Ltd.

1. No.700, Dongliu Road, Binjiang District, Hangzhou City, Zhejiang,

310052, China

2. No.299, Qiushi Road, Tonglu Economic Development Zone, Tonglu Address of Factory:

County, Hangzhou, Zhejiang, 310052, China

3. No. 555, Qianmo Road, Binjiang District, Hangzhou City, Zhejiang

Province, China

Equipment Under Test (EUT):

FUT Name: NETWORK CAMERA Model No.: DS-2CD2545FWD-IWS

Add Model No.: Refer to Page 2

FCC Rules 47 CFR §2.1091

KDB447498 D01 General RF Exposure Guidance v06 Standard(s):

RSS-102 Issue 5 (March 2015)

2020-01-09 Date of Receipt:

2020-01-09 to 2020-01-20 **Date of Test:**

2020-01-21 Date of Issue:

Pass* **Test Result:**

Parlam Zhan **E&E Section Manager**

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

中国・上海・松江区金都西路588号

pprovals in writing.

Unless otherwise agreed in writing, this document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at http://www.sgs.com/en/Terms-and-Conditions.aspx and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at http://www.sgs.com/en/Terms-and-Conditions/Terms-e-Document.aspx. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested and such sample(s) are retained for 30 days only.

Attention: To check the authenticity of testing /inspection report & certificate, please contact us at telephone: (86-755) 8307 1443,

NO.588 West Jindu Road, Songjiang District, Shanghai, China 201612 t(86-21) 61915666 f(86-21) 61915678 www.sgsgroup.com.cn t(86-21) 61915666 f(86-21) 61915678 e sgs.china@sgs.com

^{*} In the configuration tested, the EUT complied with the standards specified above.



Report No.: SHEM200100031602

Page: 2 of 9

Model No.:

For FCC model:

DS-2CD2545FWD-IWS.DS-2CD2545FWD-IWSUHK.DS-2CD2545FWD-IWSCKV.DS-2CD2555FWD-IWSCKV.DS-2CD2555FWD-IWSCKV.DS-2CD2555FWD-IWSCKV.DS-2CD255FWD-IWSCKV.DS-2CD255FWD-IWSCKV.DS-2CD255FWD-IWSCKV.DS-2CD255FWD-IWSCKV.DS-2CD255FWD-IWS IWSUVS,DS-2CD2545FWD-IWSKVO,DS-2CD2545FWD-IWSHUN,DS-2CD2525FWD-IWS,DS-2CD2525FWD-IWSUHK,DS-2CD2525FWD-IWSCKV,DS-2CD2525FWD-IWSUVS,DS-2CD2525FWD-IWSKVO,DS-2CD2525FWD-IWSHUN,DS-2CD2525FWD-IW,DS-2CD2525FWD-IWUHK,DS-2CD2525FWD-IWCKV,DS-2CD2525FWD-IWUVS,DS-2CD2525FWD-IWKVO,DS-2CD2525FWD-IWHUN,DS-2CD2535FWD-IWS,DS-2CD2535FWD-IWSUHK,DS-2CD2535FWD-IWSCKV,DS-2CD2535FWD-IWSUVS,DS-2CD2535FWD-IWSKVO,DS-2CD2535FWD-IWSHUN,DS-2CD2545FWD-IW,DS-2CD2545FWD-IWUHK,DS-2CD2545FWD-IWCKV,DS-2CD2545FWD-IWUVS,DS-2CD2545FWD-IWKVO,DS-2CD2545FWD-IWHUN,DS-2CD2555FWD-IWS,DS-2CD2555FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK,DS-2CD255FWD-IWSUHK IWSCKV,DS-2CD2555FWD-IWSUVS,DS-2CD2555FWD-IWSKVO,DS-2CD2555FWD-IWSHUN,DS-2CD2555FWD-IW,DS-2CD2555FWD-IWUHK,DS-2CD2555FWD-IWCKV,DS-2CD2555FWD-IWUVS,DS-2CD2555FWD-IWKVO,DS-2CD2555FWD-IWHUN,DS-2CD2525FHWD-IWS,DS-2CD2525FHWD-IWSUHK,DS-2CD2525FHWD-IWSCKV,DS-2CD2525FHWD-IWSUVS,DS-2CD2525FHWD-IWSKVO,DS-2CD2525FHWD-IWSHUN,DS-2CD2525FHWD-IW,DS-2CD2525FHWD-IWUHK,DS-2CD2525FHWD-IWCKV,DS-2CD2525FHWD-IWUVS,DS-2CD2525FHWD-IWKVO,DS-2CD2525FHWD-IWHUN,DS-2CD2523G0-IWS,DS-2CD2523G0-IWSUHK,DS-2CD2523G0-IWSCKV,DS-2CD2523G0-IWSUVS,DS-2CD2523G0-IWSKVO,DS-2CD2523G0-IWSHUN,DS-2CD2523G0-IW,DS-2CD2523G0-IWUHK,DS-2CD2523G0-IWCKV,DS-2CD2523G0-IWUVS,DS-2CD2523G0-IWKVO,DS-2CD2523G0-IWHUN,DS-2CD2543G0-IWS,DS-2CD2543G0-IWSUHK,DS-2CD2543G0-IWSCKV,DS-2CD2543G0-IWSUVS,DS-2CD2543G0-IWSKVO,DS-2CD2543G0-IWSHUN,DS-2CD2543G0-IW,DS-2CD2543G0-IWUHK,DS-2CD2543G0-IWCKV,DS-2CD2543G0-IWUVS,DS-2CD2543G0-IWKVO,DS-2CD2543G0-IWHUN,DS-2CD2563G0-IWS,DS-2CD2563G0-IWSUHK,DS-2CD2563G0-IWSCKV,DS-2CD2563G0-IWSUVS,DS-2CD2563G0-IWSKVO,DS-2CD2563G0-IWSHUN,DS-2CD2563G0-IW,DS-2CD2563G0-IWUHK,DS-2CD2563G0-IWCKV,DS-2CD2563G0-IWUVS,DS-2CD2563G0-IWKVO,DS-2CD2563G0-IWHUN

For IC model: DS-2CD2545FWD-IWS, DS-2CD2545FWD-IW, DS-2CD2525FWD-IWS, DS-2CD2525FWD-IW, DS-2CD2555FWD-IWS, DS-2CD2525FHWD-IWS, DS-2CD2525FHWD-IW, DS-2CD2535FWD-IWS



Report No.: SHEM200100031602

Page: 3 of 9

Revision Record					
Version	Description	Date	Remark		
00	Original	2020-01-21	/		

Authorized for issue by:			
	Michael Nill		
	Micheal Niu / Project Engineer	_	
	Parlam Zhan		
	Parlam Zhan /Reviewer	-	



Report No.: SHEM200100017803

Page: 4 of 9

2 Contents

		Pa	age
1	С	OVER PAGE	1
2	С	CONTENTS	4
3	G	GENERAL INFORMATION	5
	3.1	GENERAL DESCRIPTION OF E.U.T	5
	3.2	TECHNICAL SPECIFICATIONS	5
		TEST LOCATION	
	3.4	TEST FACILITY	6
4	Т	EST STANDARDS AND LIMITS	7
	4.1	FCC RADIOFREQUENCY RADIATION EXPOSURE LIMITS:	7
	4.2	IC RADIOFREQUENCY RADIATION EXPOSURE LIMITS:	7
5	N	MEASUREMENT AND CALCULATION	8
	5.1	MAXIMUM TRANSMIT POWER	8
	5.2	MPE CALCULATION	9



Report No.: SHEM200100017803

Page: 5 of 9

3 General Information

3.1 General Description of E.U.T.

Power supply:	DC 12V 0.7A or PoE (802.3af, 36-57V) 0.3A
Test voltage:	AC 120V 60Hz

3.2 Technical Specifications

2.4G WiFi

Antenna Gain	0dBi
Antenna Type	FPC Antenna
Channel Spacing	5MHz
Modulation Type	802.11b: DSSS (CCK, DQPSK, DBPSK) 802.11g/n: OFDM (64QAM, 16QAM, QPSK, BPSK)
Number of Channels	802.11b/g/n(HT20):11 802.11n(HT40):7
Operation Frequency	802.11b/g/n(HT20): 2412MHz to 2462MHz 802.11n(HT40): 2422MHz to 2452MHz



Report No.: SHEM200100017803

Page: 6 of 9

3.3 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. E&E Lab 588 West Jindu Road, Xinqiao, Songjiang, 201612 Shanghai, China

Tel: +86 21 6191 5666 Fax: +86 21 6191 5678

No tests were sub-contracted.

3.4 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS (No. CNAS L0599)

CNAS has accredited SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. to ISO/IEC 17025:2017 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

• NVLAP (LAB CODE: 201034-0)

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP).

FCC (Designation Number: CN5033)

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been recognized as an accredited testing laboratory. Test Firm Registration Number: 479755.

ISED (CAB Identifier: CN0020)

SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. EMC Laboratory has been recognized by Innovation, Science and Economic Development Canada (ISED) as an accredited testing laboratory. ISED#: 8617A.

VCCI (Member No.: 3061)

The 3m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services (Shanghai) Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-13868, C-14336, T-12221, G-10830 respectively.



Report No.: SHEM200100017803

Page: 7 of 9

4 Test Standards and Limits

4.1 FCC Radiofrequency radiation exposure limits:

According to §1.1310, the limit for general population/uncontrolled exposures

Frequency	Power density(mW/cm²)	Averaging time(minutes)	
300MHz~1.5GHz	f/1500	30	
1.5GHz~100GHz	1.0	30	

4.2 IC Radiofrequency radiation exposure limits:

According to RSS-102 section 2.5.2, RF exposure evaluation is required if the separation distance between the user and/or bystander and the device's radiating element is greater than 20 cm, except when the device operates as follows:

below 20 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W (adjusted for tune-up tolerance);

- at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than $4.49/f^{0.5}$ W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);
- at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 x $10^{-2} f^{0.6834}$ W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).

For 2.4G device, the limit of worse case is 2.68 W



Report No.: SHEM200100017803

Page: 8 of 9

5 Measurement and Calculation

5.1 Maximum transmit power

The Power Data is based on the RF Test Report SHEM200100031601

Test Mode	Test Channel	Ant	Power [dBm]	Power [mW]
11B	2412	Ant1	14.07	25.53
11B	2437	Ant1	14.69	29.44
11B	2462	Ant1	14.75	29.85
11G	2412	Ant1	13.25	21.13
11G	2437	Ant1	13.89	24.49
11G	2462	Ant1	13.97	24.95
11N20SISO	2412	Ant1	13.23	21.04
11N20SISO	2437	Ant1	13.87	24.38
11N20SISO	2462	Ant1	13.95	24.83
11N40SISO	2422	Ant1	12.79	19.01
11N40SISO	2437	Ant1	12.51	17.82
11N40SISO	2452	Ant1	12.60	18.20



Report No.: SHEM200100017803

Page: 9 of 9

5.2 MPE Calculation

For WiFi:

According to the formula $S=P/4\pi R^2$, we can calculate S which is MPE.

Note:

- 1) P (mW)
- 2) R = distance to the center of radiation of antenna (in meter) = 20cm
- 3) MPE limit = 1mW/cm²

The max. antenna gain is

0 dBi

Max. Conducted Power P(mW)	Gain in Linear Scale G	Operation Distance R(cm)	Power Density (mW/cm²)	Limit (mW/cm²)	Result
29.85	1.000	20	0.00594	1	Pass

For IC:

E.I.R.P.= P*G= 0.02985x1=0.02985W<2.68W

So the device is exclusion from SAR test.

-- End of the Report--